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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	7904
Number of Logic Elements/Cells	79040
Total RAM Bits	7427520
Number of I/O	773
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s80f1020c7n



Section I. Stratix Device Family Data Sheet

This section provides the data sheet specifications for Stratix® devices. They contain feature definitions of the internal architecture, configuration and JTAG boundary-scan testing information, DC operating conditions, AC timing parameters, a reference to power consumption, and ordering information for Stratix devices.

This section contains the following chapters:

- Chapter 1, Introduction
- Chapter 2, Stratix Architecture
- Chapter 3, Configuration & Testing
- Chapter 4, DC & Switching Characteristics
- Chapter 5, Reference & Ordering Information

Revision History

The table below shows the revision history for Chapters 1 through 5.

Chapter	Date/Version	Changes Made
1	July 2005, v3.2	● Minor content changes.
	September 2004, v3.1	● Updated Table 1–6 on page 1–5.
	April 2004, v3.0	● Main section page numbers changed on first page. ● Changed PCI-X to PCI-X 1.0 in “Features” on page 1–2. ● Global change from SignalTap to SignalTap II. ● The DSP blocks in “Features” on page 1–2 provide dedicated implementation of multipliers that are now “faster than 300 MHz.”
	January 2004, v2.2	● Updated -5 speed grade device information in Table 1-6.
	October 2003, v2.1	● Add -8 speed grade device information.
	July 2003, v2.0	● Format changes throughout chapter.

Introduction

The Stratix® family of FPGAs is based on a 1.5-V, 0.13-μm, all-layer copper SRAM process, with densities of up to 79,040 logic elements (LEs) and up to 7.5 Mbits of RAM. Stratix devices offer up to 22 digital signal processing (DSP) blocks with up to 176 (9-bit × 9-bit) embedded multipliers, optimized for DSP applications that enable efficient implementation of high-performance filters and multipliers. Stratix devices support various I/O standards and also offer a complete clock management solution with its hierarchical clock structure with up to 420-MHz performance and up to 12 phase-locked loops (PLLs).

The following shows the main sections in the Stratix Device Family Data Sheet:

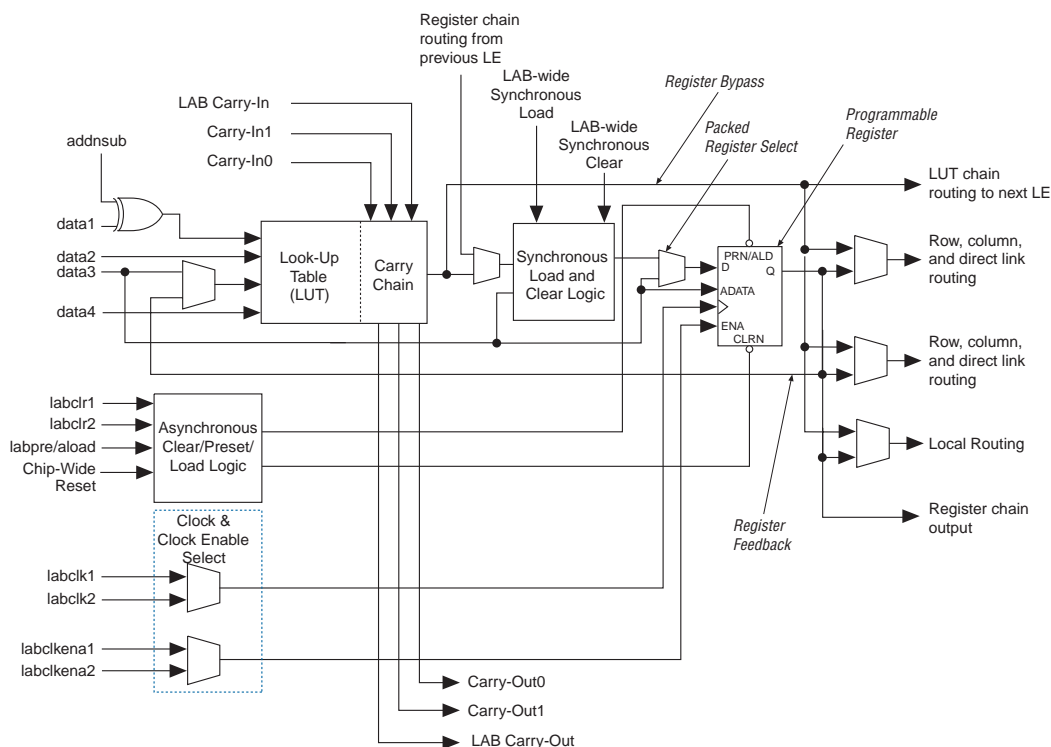
Section	Page
Features	1-2
Functional Description	2-1
Logic Array Blocks	2-3
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Features

The Stratix family offers the following features:

- 10,570 to 79,040 LEs; see [Table 1–1](#)
- Up to 7,427,520 RAM bits (928,440 bytes) available without reducing logic resources
- TriMatrix™ memory consisting of three RAM block sizes to implement true dual-port memory and first-in first-out (FIFO) buffers
- High-speed DSP blocks provide dedicated implementation of multipliers (faster than 300 MHz), multiply-accumulate functions, and finite impulse response (FIR) filters
- Up to 16 global clocks with 22 clocking resources per device region
- Up to 12 PLLs (four enhanced PLLs and eight fast PLLs) per device provide spread spectrum, programmable bandwidth, clock switch-over, real-time PLL reconfiguration, and advanced multiplication and phase shifting
- Support for numerous single-ended and differential I/O standards
- High-speed differential I/O support on up to 116 channels with up to 80 channels optimized for 840 megabits per second (Mbps)
- Support for high-speed networking and communications bus standards including RapidIO, UTOPIA IV, CSIX, HyperTransport™ technology, 10G Ethernet XSBI, SPI-4 Phase 2 (POS-PHY Level 4), and SFI-4
- Differential on-chip termination support for LVDS
- Support for high-speed external memory, including zero bus turnaround (ZBT) SRAM, quad data rate (QDR and QDRII) SRAM, double data rate (DDR) SDRAM, DDR fast cycle RAM (FCRAM), and single data rate (SDR) SDRAM
- Support for 66-MHz PCI (64 and 32 bit) in -6 and faster speed-grade devices, support for 33-MHz PCI (64 and 32 bit) in -8 and faster speed-grade devices
- Support for 133-MHz PCI-X 1.0 in -5 speed-grade devices
- Support for 100-MHz PCI-X 1.0 in -6 and faster speed-grade devices
- Support for 66-MHz PCI-X 1.0 in -7 speed-grade devices
- Support for multiple intellectual property megafunctions from Altera MegaCore® functions and Altera Megafunction Partners Program (AMPPSM) megafunctions
- Support for remote configuration updates

Figure 2–5. Stratix LE



Each LE's programmable register can be configured for D, T, JK, or SR operation. Each register has data, true asynchronous load data, clock, clock enable, clear, and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous data. The asynchronous load data input comes from the data3 input of the LE. For combinational functions, the register is bypassed and the output of the LUT drives directly to the outputs of the LE.

Each LE has three outputs that drive the local, row, and column routing resources. The LUT or register output can drive these three outputs independently. Two LE outputs drive column or row and direct link routing connections and one drives local interconnect resources. This allows the LUT to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the LUT for unrelated

M-RAM Block

The largest TriMatrix memory block, the M-RAM block, is useful for applications where a large volume of data must be stored on-chip. Each block contains 589,824 RAM bits (including parity bits). The M-RAM block can be configured in the following modes:

- True dual-port RAM
- Simple dual-port RAM
- Single-port RAM
- FIFO RAM

You cannot use an initialization file to initialize the contents of a M-RAM block. All M-RAM block contents power up to an undefined value. Only synchronous operation is supported in the M-RAM block, so all inputs are registered. Output registers can be bypassed. The memory address and output width can be configured as $64\text{K} \times 8$ (or $64\text{K} \times 9$ bits), $32\text{K} \times 16$ (or $32\text{K} \times 18$ bits), $16\text{K} \times 32$ (or $16\text{K} \times 36$ bits), $8\text{K} \times 64$ (or $8\text{K} \times 72$ bits), and $4\text{K} \times 128$ (or $4\text{K} \times 144$ bits). The $4\text{K} \times 128$ configuration is unavailable in true dual-port mode because there are a total of 144 data output drivers in the block. Mixed-width configurations are also possible, allowing different read and write widths. [Tables 2-8](#) and [2-9](#) summarize the possible M-RAM block configurations:

Table 2-8. M-RAM Block Configurations (Simple Dual-Port)					
Read Port	Write Port				
	$64\text{K} \times 9$	$32\text{K} \times 18$	$16\text{K} \times 36$	$8\text{K} \times 72$	$4\text{K} \times 144$
$64\text{K} \times 9$	✓	✓	✓	✓	
$32\text{K} \times 18$	✓	✓	✓	✓	
$16\text{K} \times 36$	✓	✓	✓	✓	
$8\text{K} \times 72$	✓	✓	✓	✓	
$4\text{K} \times 144$					✓

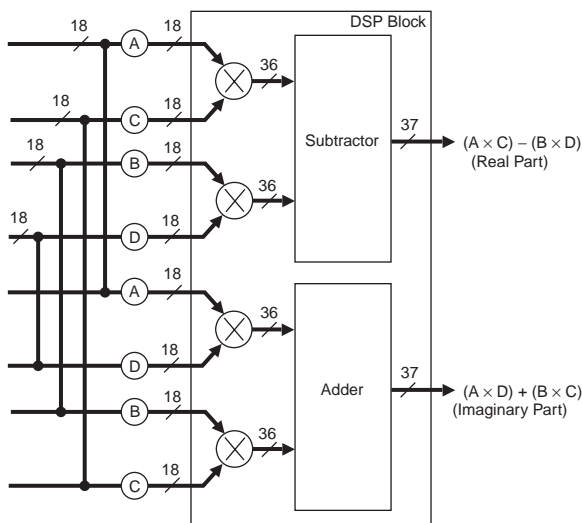
single DSP block can implement two sums or differences from two 18×18 -bit multipliers each or four sums or differences from two 9×9 -bit multipliers each.

You can use the two-multipliers adder mode for complex multiplications, which are written as:

$$(a + jb) \times (c + jd) = [(a \times c) - (b \times d)] + j \times [(a \times d) + (b \times c)]$$

The two-multipliers adder mode allows a single DSP block to calculate the real part $[(a \times c) - (b \times d)]$ using one subtractor and the imaginary part $[(a \times d) + (b \times c)]$ using one adder, for data widths up to 18 bits. Two complex multiplications are possible for data widths up to 9 bits using four adder/subtractor/accumulator blocks. Figure 2–38 shows an 18-bit two-multipliers adder.

Figure 2–38. Two-Multipliers Adder Mode Implementing Complex Multiply



Four-Multipliers Adder Mode

In the four-multipliers adder mode, the DSP block adds the results of two first-stage adder/subtractor blocks. One sum of four 18×18 -bit multipliers or two different sums of two sets of four 9×9 -bit multipliers can be implemented in a single DSP block. The product width for each multiplier must be the same size. The four-multipliers adder mode is useful for FIR filter applications. Figure 2–39 shows the four multipliers adder mode.

provide general purpose clocking with multiplication and phase shifting as well as high-speed outputs for high-speed differential I/O support. Enhanced and fast PLLs work together with the Stratix high-speed I/O and advanced clock architecture to provide significant improvements in system performance and bandwidth.

The Quartus II software enables the PLLs and their features without requiring any external devices. Table 2–18 shows the PLLs available for each Stratix device.

Table 2–18. Stratix Device PLL Availability

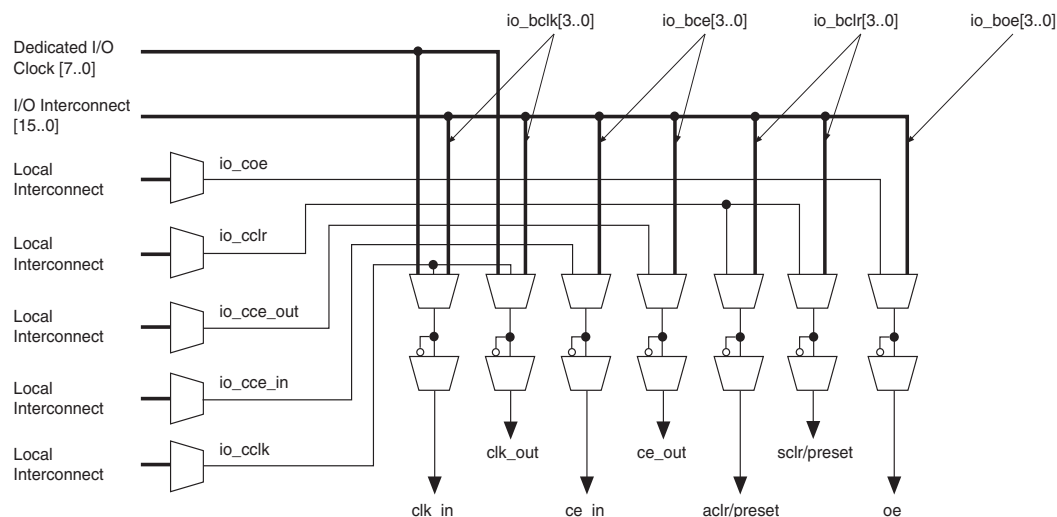
Device	Fast PLLs								Enhanced PLLs			
	1	2	3	4	7	8	9	10	5(1)	6(1)	11(2)	12(2)
EP1S10	✓	✓	✓	✓					✓	✓		
EP1S20	✓	✓	✓	✓					✓	✓		
EP1S25	✓	✓	✓	✓					✓	✓		
EP1S30	✓	✓	✓	✓	✓ (3)	✓ (3)	✓ (3)	✓ (3)	✓	✓		
EP1S40	✓	✓	✓	✓	✓ (3)	✓ (3)	✓ (3)	✓ (3)	✓	✓	✓ (3)	✓ (3)
EP1S60	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓
EP1S80	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓

Notes to Table 2–18:

- (1) PLLs 5 and 6 each have eight single-ended outputs or four differential outputs.
- (2) PLLs 11 and 12 each have one single-ended output.
- (3) EP1S30 and EP1S40 devices do not support these PLLs in the 780-pin FineLine BGA® package.

Each IOE contains its own control signal selection for the following control signals: oe, ce_in, ce_out, aclr/preset, sclr/preset, clk_in, and clk_out. Figure 2-63 illustrates the control signal selection.

Figure 2-63. Control Signal Selection per IOE



In normal bidirectional operation, the input register can be used for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register can be used for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from local interconnect in the associated LAB, dedicated I/O clocks, and the column and row interconnects. Figure 2-64 shows the IOE in bidirectional configuration.

and/or output enable registers. A programmable delay exists to increase the t_{ZX} delay to the output pin, which is required for ZBT interfaces.

Table 2–24 shows the programmable delays for Stratix devices.

Table 2–24. Stratix Programmable Delay Chain	
Programmable Delays	Quartus II Logic Option
Input pin to logic array delay	Decrease input delay to internal cells
Input pin to input register delay	Decrease input delay to input register
Output pin delay	Increase delay to output pin
Output enable register t_{CO} delay	Increase delay to output enable pin
Output t_{ZX} delay	Increase t_{ZX} delay to output pin
Output clock enable delay	Increase output clock enable delay
Input clock enable delay	Increase input clock enable delay
Logic array to output register delay	Decrease input delay to output register
Output enable clock enable delay	Increase output enable clock enable delay

The IOE registers in Stratix devices share the same source for clear or preset. You can program preset or clear for each individual IOE. You can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power-up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally a synchronous reset signal is available for the IOE registers.

Double-Data Rate I/O Pins

Stratix devices have six registers in the IOE, which support DDR interfacing by clocking data on both positive and negative clock edges. The IOEs in Stratix devices support DDR inputs, DDR outputs, and bidirectional DDR modes.

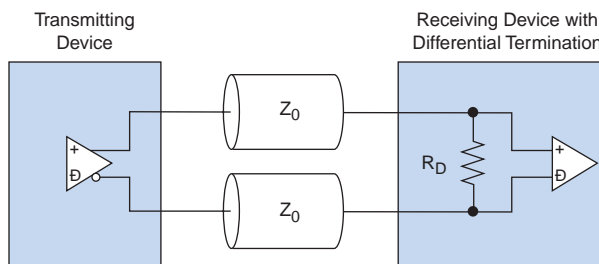
When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used within the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times. This allows both bits of data to be synchronous with the same clock edge (either rising or falling).

Figure 2–65 shows an IOE configured for DDR input. Figure 2–66 shows the DDR input timing diagram.



For more information on I/O standards supported by Stratix devices, see the *Selectable I/O Standards in Stratix & Stratix GX Devices* chapter of the *Stratix Device Handbook, Volume 2*.

Stratix devices contain eight I/O banks in addition to the four enhanced PLL external clock out banks, as shown in [Figure 2–70](#). The four I/O banks on the right and left of the device contain circuitry to support high-speed differential I/O for LVDS, LVPECL, 3.3-V PCML, and HyperTransport inputs and outputs. These banks support all I/O standards listed in [Table 2–31](#) except PCI I/O pins or PCI-X 1.0, GTL, SSTL-18 Class II, and HSTL Class II outputs. The top and bottom I/O banks support all single-ended I/O standards. Additionally, Stratix devices support four enhanced PLL external clock output banks, allowing clock output capabilities such as differential support for SSTL and HSTL. [Table 2–32](#) shows I/O standard support for each I/O bank.

Figure 2–71. LVDS Input Differential On-Chip Termination

I/O banks on the left and right side of the device support LVDS receiver (far-end) differential termination.

Table 2–33 shows the Stratix device differential termination support.

Table 2–33. Differential Termination Supported by I/O Banks			
Differential Termination Support	I/O Standard Support	Top & Bottom Banks (3, 4, 7 & 8)	Left & Right Banks (1, 2, 5 & 6)
Differential termination (1), (2)	LVDS		✓

Notes to Table 2–33:

- (1) Clock pin CLK0, CLK2, CLK9, CLK11, and pins FPLL[7..10] CLK do not support differential termination.
- (2) Differential termination is only supported for LVDS because of a 3.3-V V_{CCIO} .

Table 2–34 shows the termination support for different pin types.

Table 2–34. Differential Termination Support Across Pin Types	
Pin Type	R_D
Top and bottom I/O banks (3, 4, 7, and 8)	
DIFFIO_RX[]	✓
CLK[0, 2, 9, 11], CLK[4–7], CLK[12–15]	
CLK[1, 3, 8, 10]	✓
FCLK	
FPLL[7..10] CLK	

The differential on-chip resistance at the receiver input buffer is $118\ \Omega \pm 20\%$.

synthesis, allowing real-time variation of the PLL frequency and delay. The rest of the device is functional while reconfiguring the PLL. See the *Stratix Architecture* chapter of the *Stratix Device Handbook, Volume 1* for more information on Stratix PLLs.

Remote Update Configuration Modes

Stratix devices also support remote configuration using an Altera enhanced configuration device (e.g., EPC16, EPC8, and EPC4 devices) with page mode selection. Factory configuration data is stored in the default page of the configuration device. This is the default configuration that contains the design required to control remote updates and handle or recover from errors. You write the factory configuration once into the flash memory or configuration device. Remote update data can update any of the remaining pages of the configuration device. If there is an error or corruption in a remote update configuration, the configuration device reverts back to the factory configuration information.

There are two remote configuration modes: remote and local configuration. You can use the remote update configuration mode for all three configuration modes: serial, parallel synchronous, and parallel asynchronous. Configuration devices (for example, EPC16 devices) only support serial and parallel synchronous modes. Asynchronous parallel mode allows remote updates when an intelligent host is used to configure the Stratix device. This host must support page mode settings similar to an EPC16 device.

Remote Update Mode

When the Stratix device is first powered up in remote update programming mode, it loads the configuration located at page address "000." The factory configuration should always be located at page address "000," and should never be remotely updated. The factory configuration contains the required logic to perform the following operations:

- Determine the page address/load location for the next application's configuration data
- Recover from a previous configuration error
- Receive new configuration data and write it into the configuration device

The factory configuration is the default and takes control if an error occurs while loading the application configuration.

Table 4–50. M-RAM Block Internal Timing Microparameters (Part 2 of 2)

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{MRAMBESU}	25		25		28		33		ps
t_{MRAMBEH}	18		20		23		27		ps
$t_{\text{MRAMDATAASU}}$	25		25		28		33		ps
$t_{\text{MRAMDATAAH}}$	18		20		23		27		ps
$t_{\text{MRAMADDRASU}}$	25		25		28		33		ps
$t_{\text{MRAMADDRAH}}$	18		20		23		27		ps
$t_{\text{MRAMDATABSU}}$	25		25		28		33		ps
$t_{\text{MRAMDATABH}}$	18		20		23		27		ps
$t_{\text{MRAMADDRBSU}}$	25		25		28		33		ps
$t_{\text{MRAMADDRBH}}$	18		20		23		27		ps
$t_{\text{MRAMDATA CO1}}$		1,038		1,053		1,210		1,424	ps
$t_{\text{MRAMDATA CO2}}$		4,362		4,939		5,678		6,681	ps
$t_{\text{MRAMCLKHL}}$	1,000		1,111		1,190		1,400		ps
t_{MRAMCLR}	135		150		172		202		ps

Table 4–51. Routing Delay Internal Timing Parameters

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{R4}		268		295		339		390	ps
t_{R8}		371		349		401		461	ps
t_{R24}		465		512		588		676	ps
t_{C4}		440		484		557		641	ps
t_{C8}		577		634		730		840	ps
t_{C16}		445		489		563		647	ps
t_{LOCAL}		313		345		396		455	ps

Routing delays vary depending on the load on that specific routing line. The Quartus II software reports the routing delay information when running the timing analysis for a design.

Table 4–65. EP1S20 External I/O Timing on Row Pins Using Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.815		1.967		2.258		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.633	5.235	2.663	5.595	2.663	6.070	NA	NA	ns
t_{XZ}	2.660	5.289	2.660	5.651	2.660	6.138	NA	NA	ns
t_{ZX}	2.660	5.289	2.660	5.651	2.660	6.138	NA	NA	ns
t_{INSUPLL}	1.060		1.112		1.277		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.325	2.770	1.325	2.908	1.325	2.978	NA	NA	ns
t_{XZPLL}	1.352	2.824	1.352	2.964	1.352	3.046	NA	NA	ns
t_{ZXPLL}	1.352	2.824	1.352	2.964	1.352	3.046	NA	NA	ns

Table 4–66. EP1S20 External I/O Timing on Row Pins Using Global Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.742		1.887		2.170		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.674	5.308	2.674	5.675	2.674	6.158	NA	NA	ns
t_{XZ}	2.701	5.362	2.701	5.731	2.701	6.226	NA	NA	ns
t_{ZX}	2.701	5.362	2.701	5.731	2.701	6.226	NA	NA	ns
t_{INSUPLL}	1.353		1.418		1.613		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.158	2.447	1.158	2.602	1.158	2.642	NA	NA	ns
t_{XZPLL}	1.185	2.531	1.158	2.602	1.185	2.710	NA	NA	ns
t_{ZXPLL}	1.185	2.531	1.158	2.602	1.185	2.710	NA	NA	ns

Note to Tables 4–61 to 4–66:

(1) Only EP1S25, EP1S30, and EP1S40 have a speed grade of -8.

Table 4–81. EP1S40 External I/O Timing on Column Pins Using Global Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.126		2.268		2.558		2.930		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.856	5.585	2.856	5.987	2.856	6.541	2.847	7.253	ns
t_{XZ}	2.796	5.459	2.796	5.855	2.796	6.417	2.787	7.138	ns
t_{ZX}	2.796	5.459	2.796	5.855	2.796	6.417	2.787	7.138	ns
t_{INSUPLL}	1.466		1.455		1.711		1.906		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
t_{OUTCOPLL}	1.092	2.345	1.092	2.510	1.092	2.455	1.089	2.473	ns
t_{XZPLL}	1.032	2.219	1.032	2.378	1.032	2.331	1.029	2.358	ns
t_{ZXPLL}	1.032	2.219	1.032	2.378	1.032	2.331	1.029	2.358	ns

Table 4–82. EP1S40 External I/O Timing on Row Pins Using Fast Regional Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.472		2.685		3.083		3.056		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.631	5.258	2.631	5.625	2.631	6.105	2.745	7.324	ns
t_{XZ}	2.658	5.312	2.658	5.681	2.658	6.173	2.772	7.406	ns
t_{ZX}	2.658	5.312	2.658	5.681	2.658	6.173	2.772	7.406	ns

Table 4–102. Reporting Methodology For Minimum Timing For Single-Ended Output Pins (Part 2 of 2)*Notes (1), (2), (3)*

I/O Standard	Loading and Termination							Measurement Point
	R_{UP} Ω	R_{DN} Ω	R_S Ω	R_T Ω	V_{CCIO} (V)	V_{TT} (V)	C_L (pF)	V_{MEAS}
3.3-V CTT	–	–	25	50	3.600	1.650	30	1.650

Notes to Table 4–102:

- (1) Input measurement point at internal node is $0.5 \times V_{CCINT}$.
- (2) Output measuring point for data is V_{MEAS} . When two values are given, the first is the measurement point on the rising edge and the other is for the falling edge.
- (3) Input stimulus edge rate is 0 to V_{CCINT} in 0.5 ns (internal signal) from the driver preceding the I/O buffer.
- (4) The first value is for the output rising edge and the second value is for the output falling edge. The hyphen (-) indicates infinite resistance or disconnection.

Figure 4–8 shows the measurement setup for output disable and output enable timing. The T_{CHZ} stands for clock to high Z time delay and is the same as T_{XZ} . The T_{CLZ} stands for clock to low Z (driving) time delay and is the same as T_{ZX} .

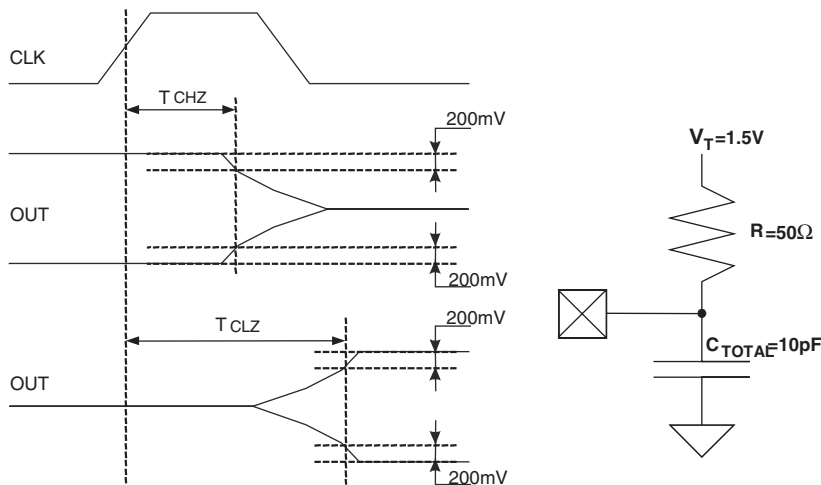
Figure 4–8. Measurement Setup for T_{XZ} and T_{ZX} 

Table 4–104. Stratix I/O Standard Row Pin Input Delay Adders

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
LVC MOS		0		0		0		0	ps
3.3-V LVTTTL		0		0		0		0	ps
2.5-V LVTTTL		21		22		25		29	ps
1.8-V LVTTTL		181		190		218		257	ps
1.5-V LVTTTL		300		315		362		426	ps
GTL+		–152		–160		–184		–216	ps
CTT		–168		–177		–203		–239	ps
SSTL-3 Class I		–193		–203		–234		–275	ps
SSTL-3 Class II		–193		–203		–234		–275	ps
SSTL-2 Class I		–262		–276		–317		–373	ps
SSTL-2 Class II		–262		–276		–317		–373	ps
SSTL-18 Class I		–105		–111		–127		–150	ps
SSTL-18 Class II		0		0		0		0	ps
1.5-V HSTL Class I		–151		–159		–183		–215	ps
1.8-V HSTL Class I		–126		–133		–153		–179	ps
LVDS		–149		–157		–180		–212	ps
LVPECL		–149		–157		–180		–212	ps
3.3-V PCML		–65		–69		–79		–93	ps
HyperTransport		77		–81		–93		–110	ps

Table 4–126. High-Speed I/O Specifications for Wire-Bond Packages (Part 1 of 2)											
Symbol	Conditions	-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK} (Clock frequency) (LVDS, LVPECL, HyperTransport technology) f _{HCLK} = f _{HSDR} / W	W = 4 to 30 (Serdes used)	10		156	10		115.5	10		115.5	MHz
	W = 2 (Serdes bypass)	50		231	50		231	50		231	MHz
	W = 2 (Serdes used)	150		312	150		231	150		231	MHz
	W = 1 (Serdes bypass)	100		311	100		270	100		270	MHz
	W = 1 (Serdes used)	300		624	300		462	300		462	MHz
f _{HSDR} Device operation, (LVDS, LVPECL, HyperTransport technology)	J = 10	300		624	300		462	300		462	Mbps
	J = 8	300		624	300		462	300		462	Mbps
	J = 7	300		624	300		462	300		462	Mbps
	J = 4	300		624	300		462	300		462	Mbps
	J = 2	100		462	100		462	100		462	Mbps
	J = 1 (LVDS and LVPECL only)	100		311	100		270	100		270	Mbps
f _{HCLK} (Clock frequency) (PCML) f _{HCLK} = f _{HSDR} / W	W = 4 to 30 (Serdes used)	10		77.75							MHz
	W = 2 (Serdes bypass)	50		150	50		77.5	50		77.5	MHz
	W = 2 (Serdes used)	150		155.5							MHz
	W = 1 (Serdes bypass)	100		200	100		155	100		155	MHz
	W = 1 (Serdes used)	300		311							MHz
Device operation, f _{HSDR} (PCML)	J = 10	300		311							Mbps
	J = 8	300		311							Mbps
	J = 7	300		311							Mbps
	J = 4	300		311							Mbps
	J = 2	100		300	100		155	100		155	Mbps
	J = 1	100		200	100		155	100		155	Mbps
TCCS	All			400			400			400	ps

Table 4–128. Enhanced PLL Specifications for -6 Speed Grades (Part 2 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
t _{SCANCLK}	scanclk frequency (5)			22	MHz
t _{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7) (11)	(9)		100	μs
t _{LOCK}	Time required to lock from end of device configuration (11)	10		400	μs
f _{VCO}	PLL internal VCO operating range	300		800 (8)	MHz
t _{LSKEW}	Clock skew between two external clock outputs driven by the same counter		±50		ps
t _{SKEW}	Clock skew between two external clock outputs driven by the different counters with the same settings		±75		ps
f _{SS}	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.4	0.5	0.6	%
t _{ARESET}	Minimum pulse width on areset signal	10			ns

Table 4–129. Enhanced PLL Specifications for -7 Speed Grade (Part 1 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
f _{IN}	Input clock frequency	3 (1), (2)		565	MHz
f _{INPFD}	Input frequency to PFD	3		420	MHz
f _{INDUTY}	Input clock duty cycle	40		60	%
f _{EINDUTY}	External feedback clock input duty cycle	40		60	%
t _{INJITTER}	Input clock period jitter			±200 (3)	ps
t _{EINJITTER}	External feedback clock period jitter			±200 (3)	ps
t _{FCOMP}	External feedback clock compensation time (4)			6	ns
f _{OUT}	Output frequency for internal global or regional clock	0.3		420	MHz
f _{OUT_EXT}	Output frequency for external clock (3)	0.3		434	MHz